

# Status Report

## - $X_p$ cut scan summary -

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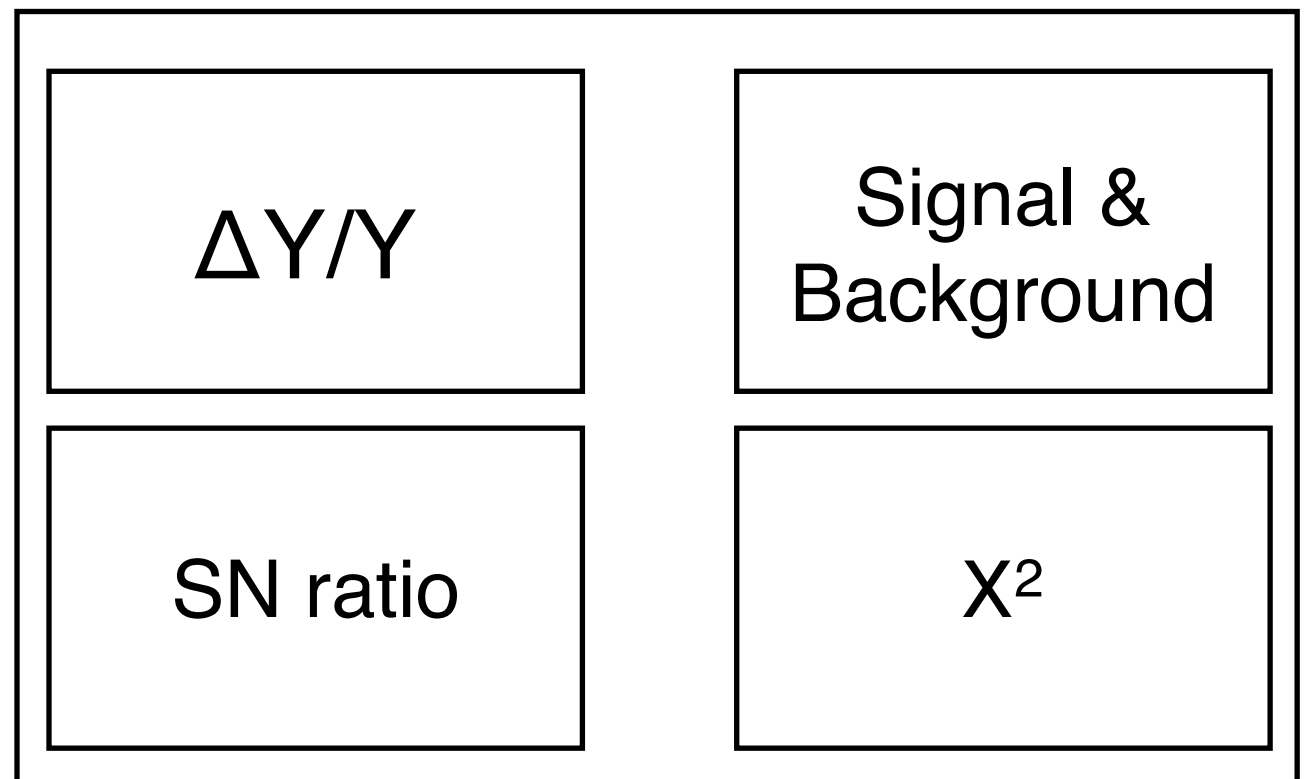
# X<sub>p</sub> cut scan summary

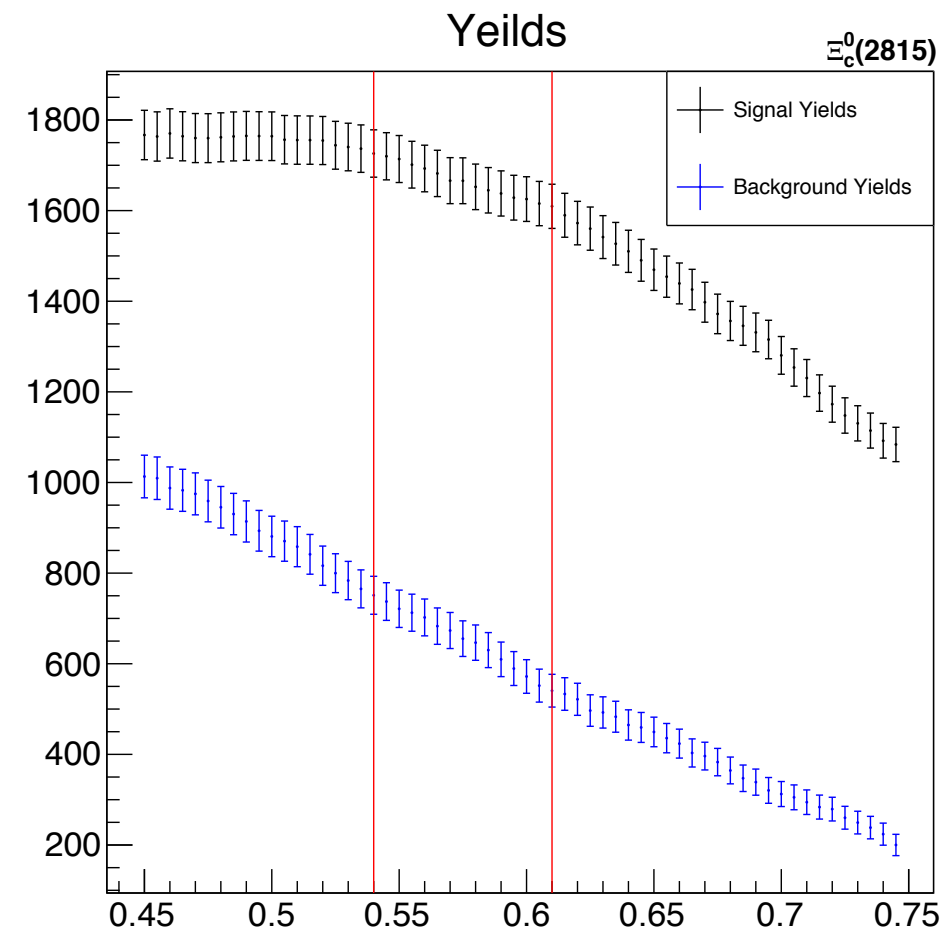
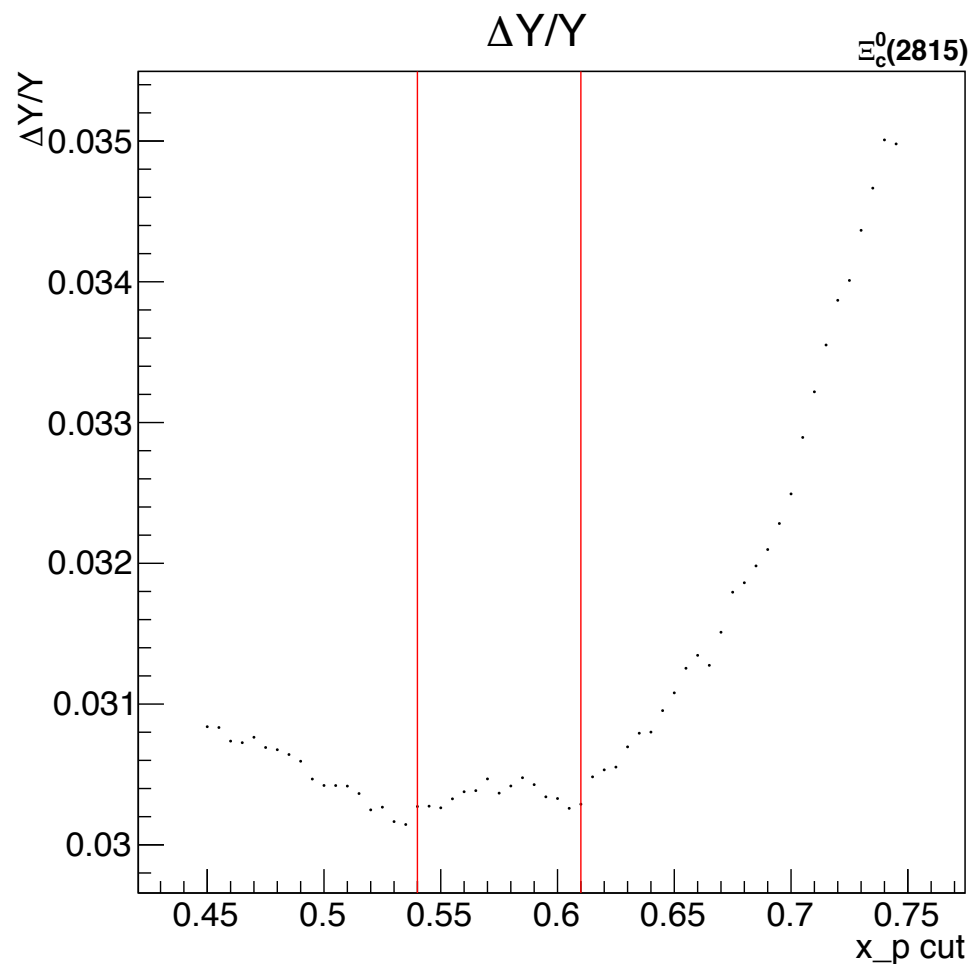
- Purpose
  - To obtain high yield with low uncertainty in yield
- Following 4 values are checked
  - $\Delta Y/Y$  (Y: signal yield)
  - Signal yield and background yield
  - S/N ratio
  - Chi square

# Contents & Layout

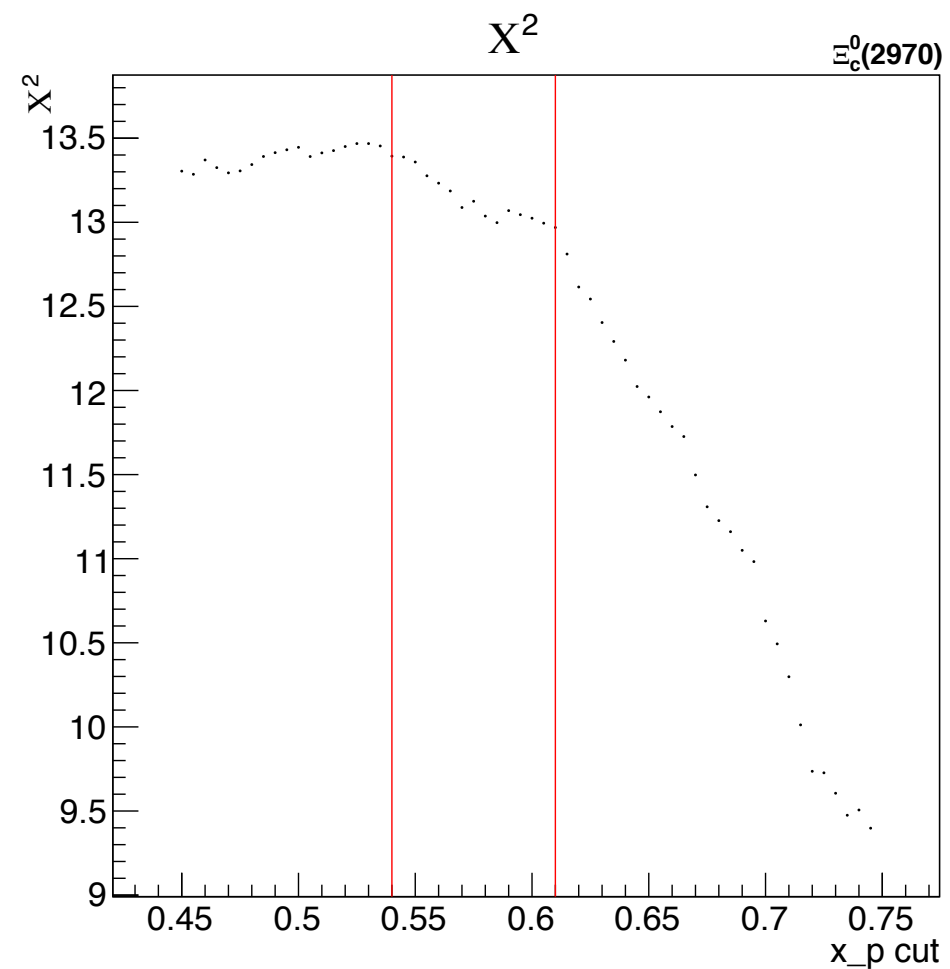
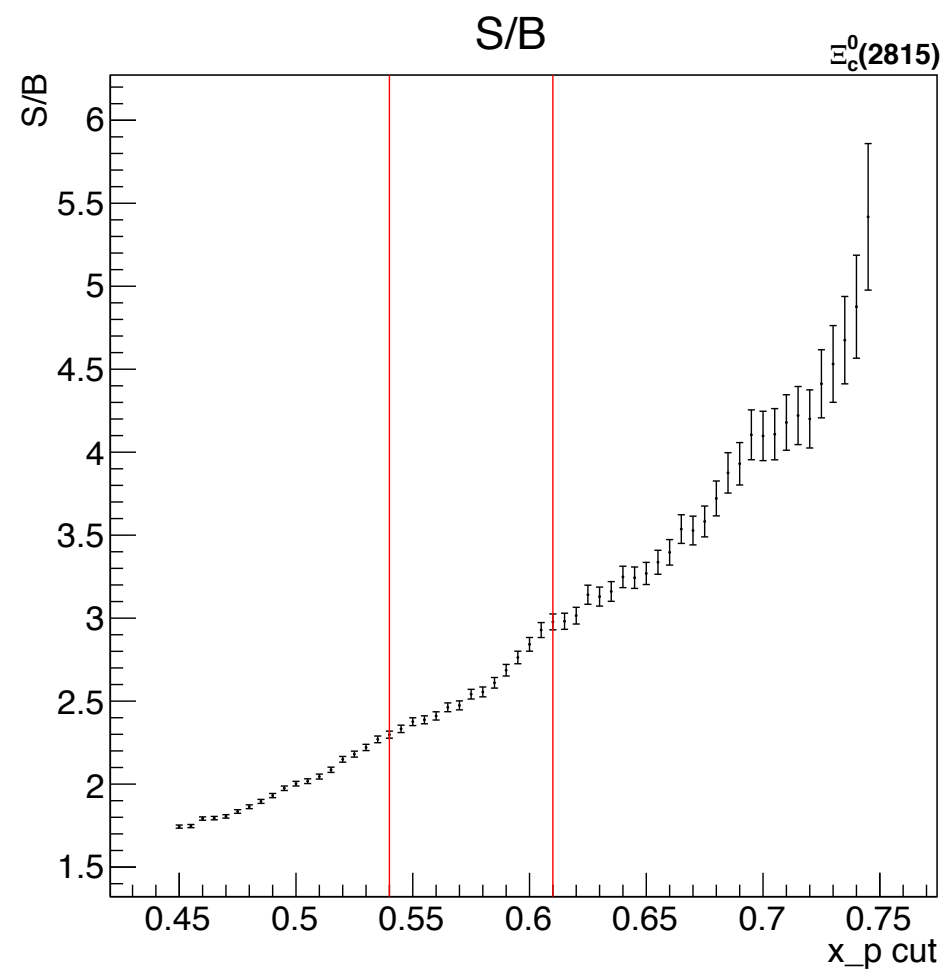
- Page 4 :  $\Xi_c^0(2815)$
- Page 5 :  $\Xi_c^+(2815)$
- Page 6 :  $\Xi_c^0(2970)$
- Page 7 :  $\Xi_c^+(2970)$

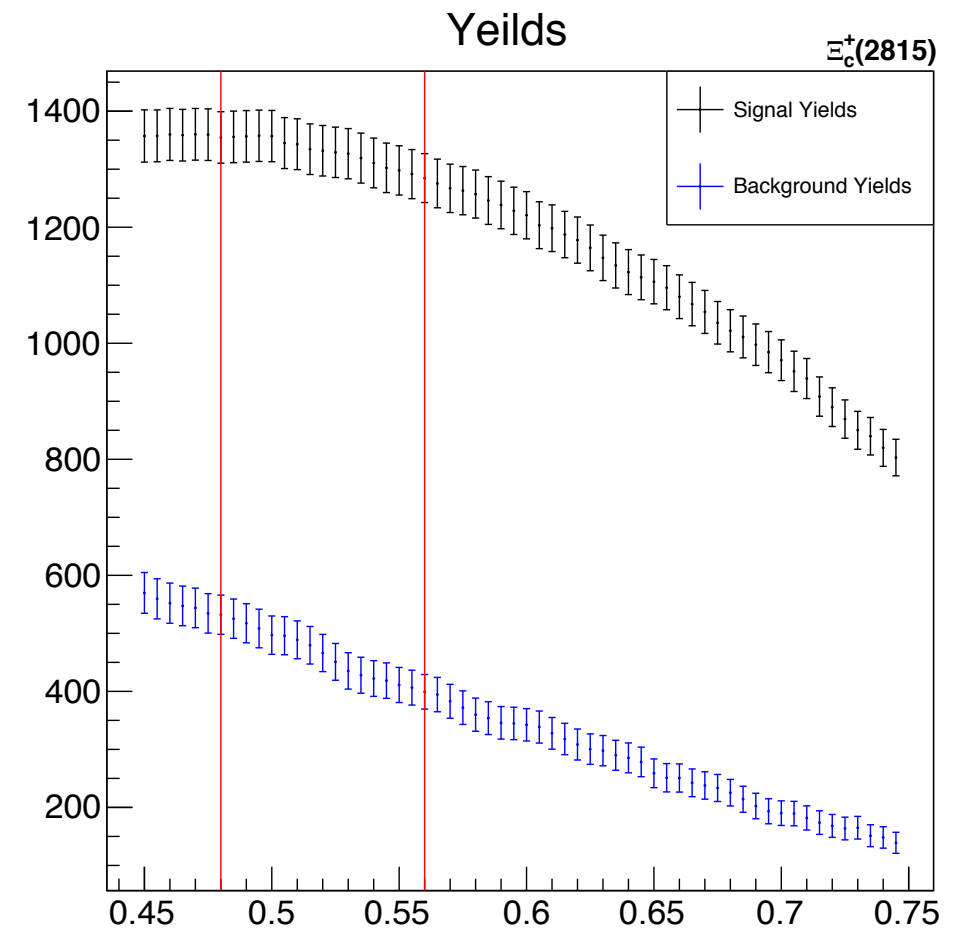
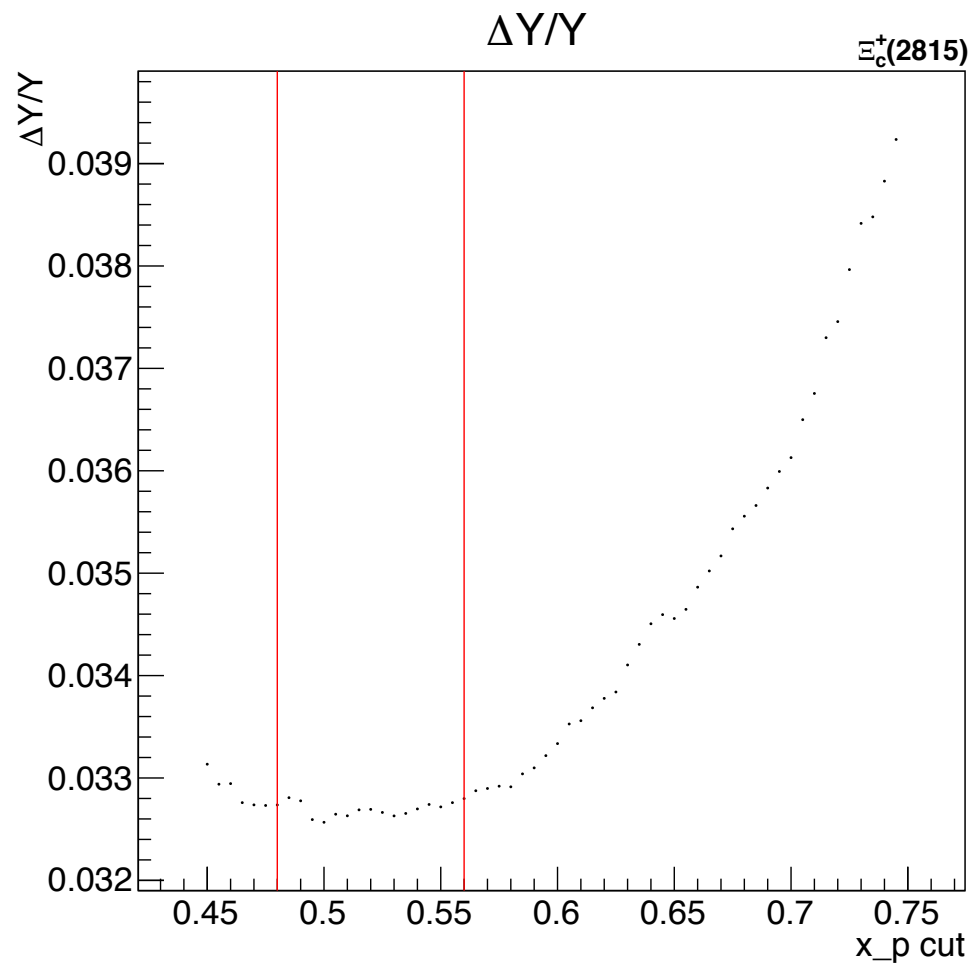
In each page,



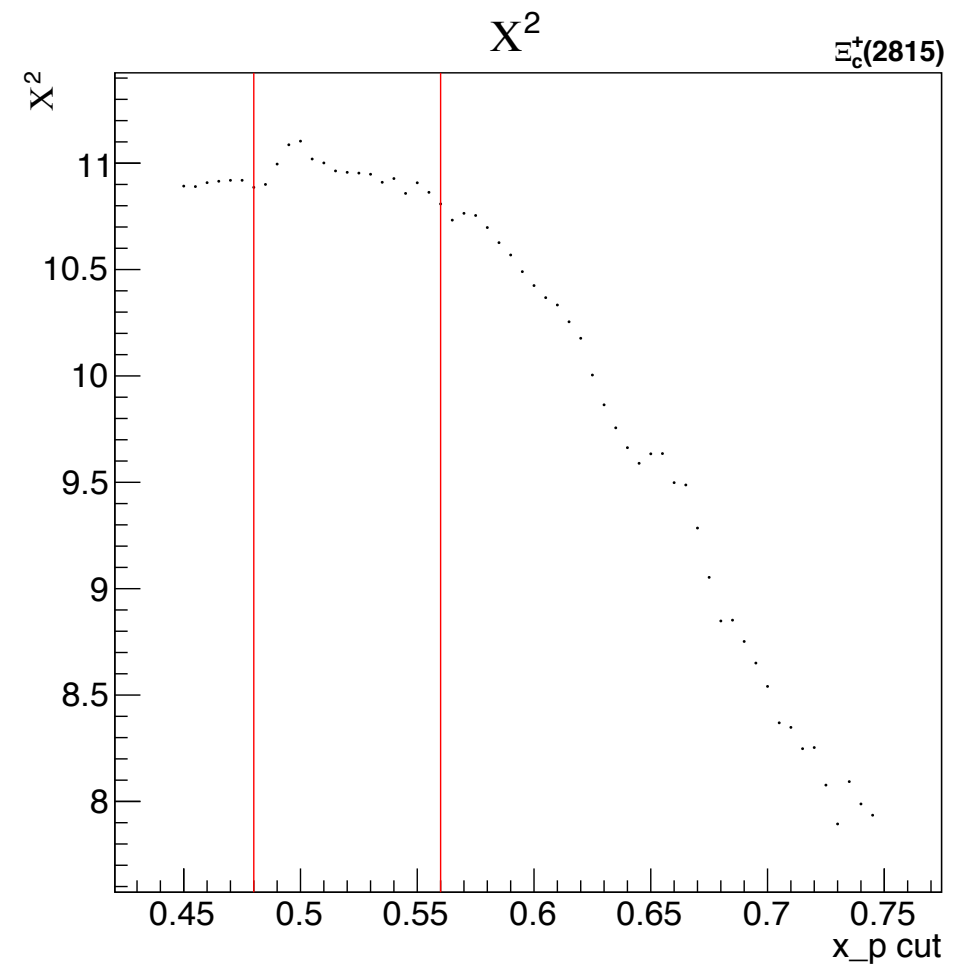
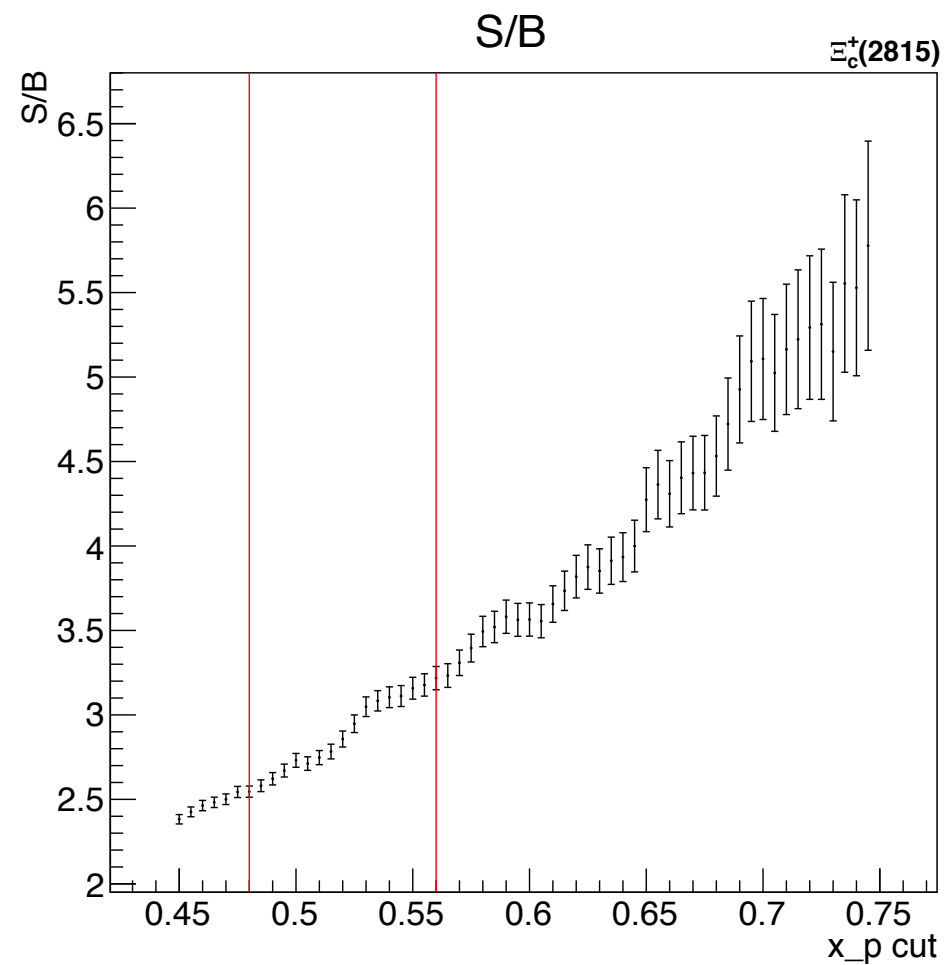


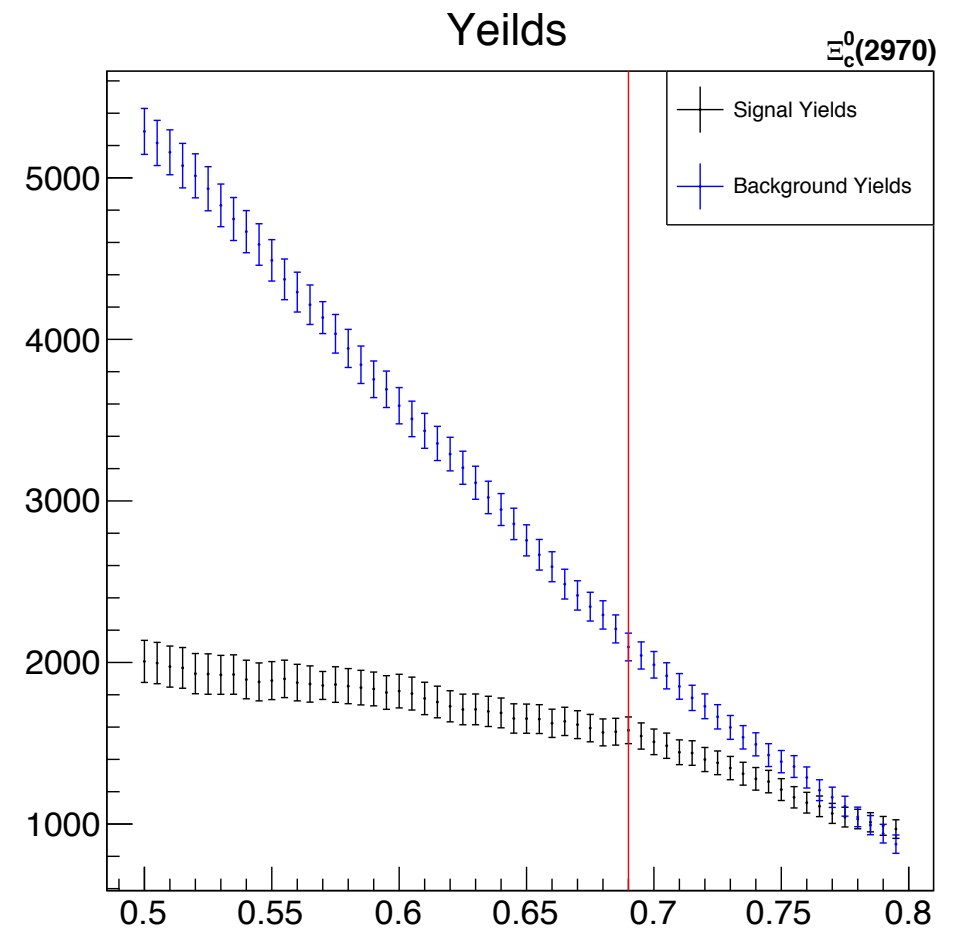
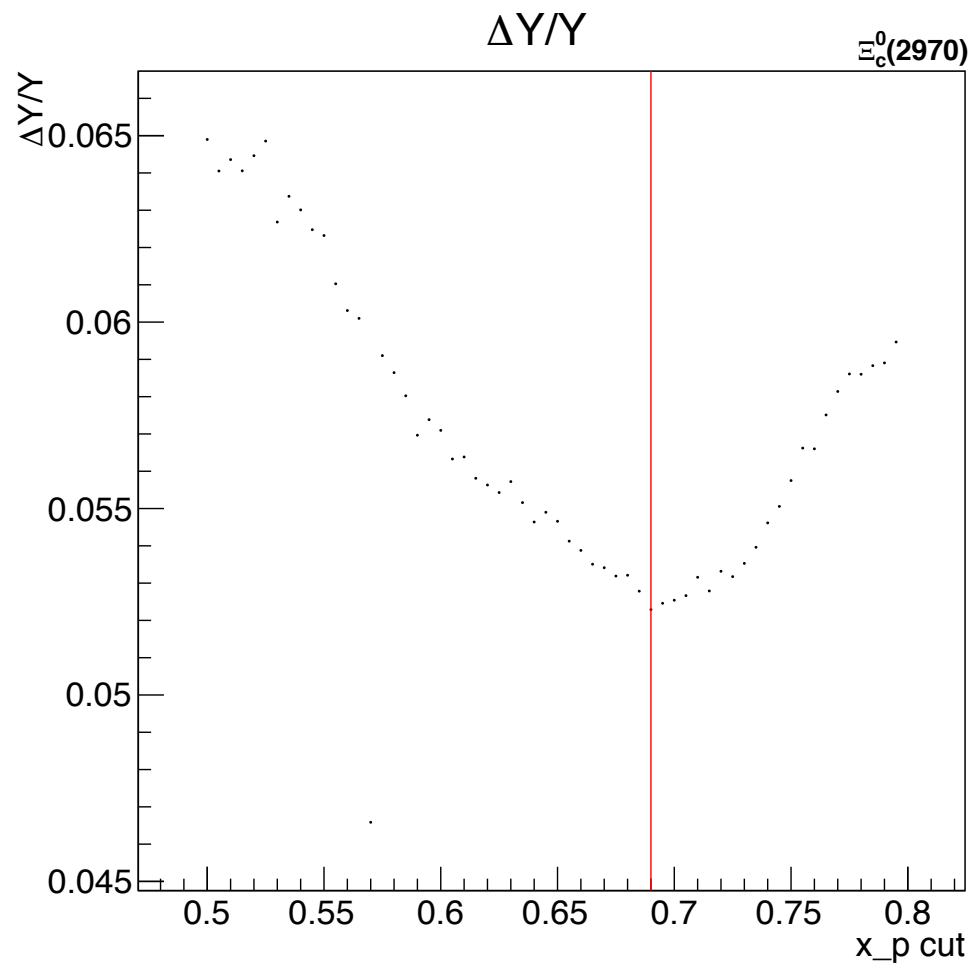
$\Xi_c^0(2815)$



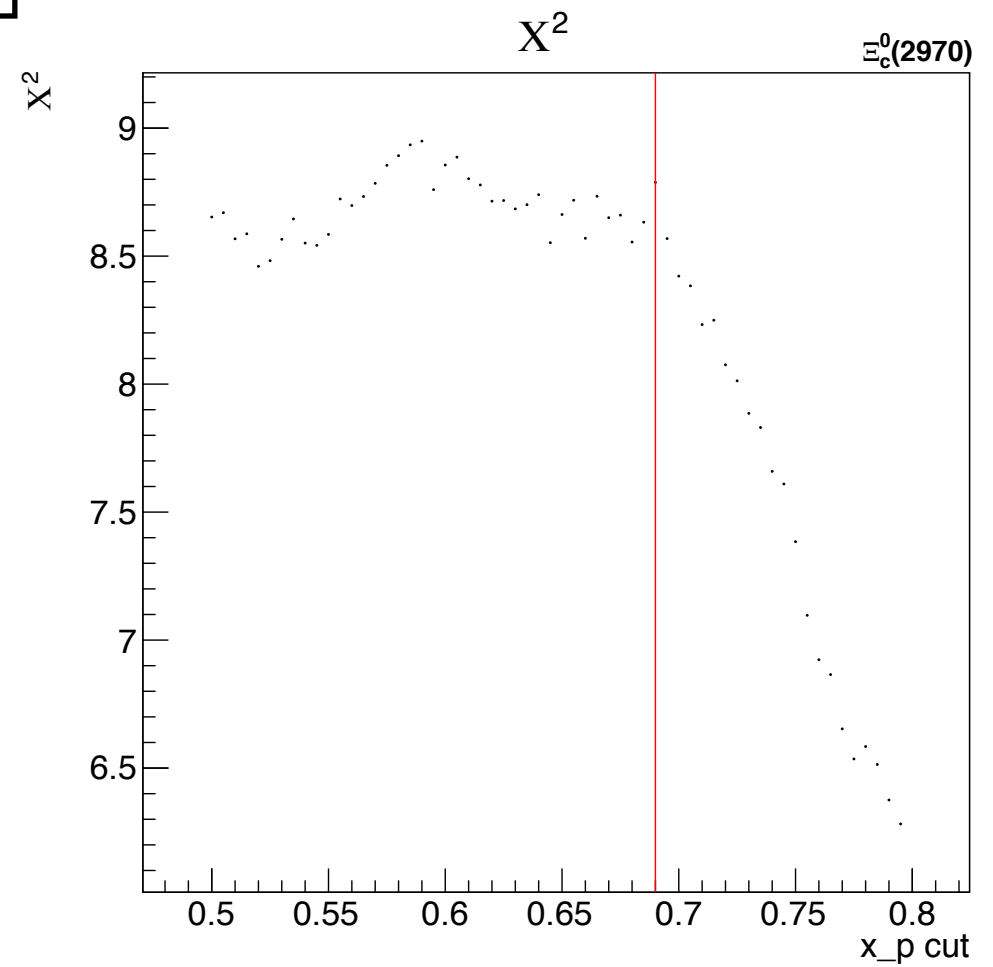
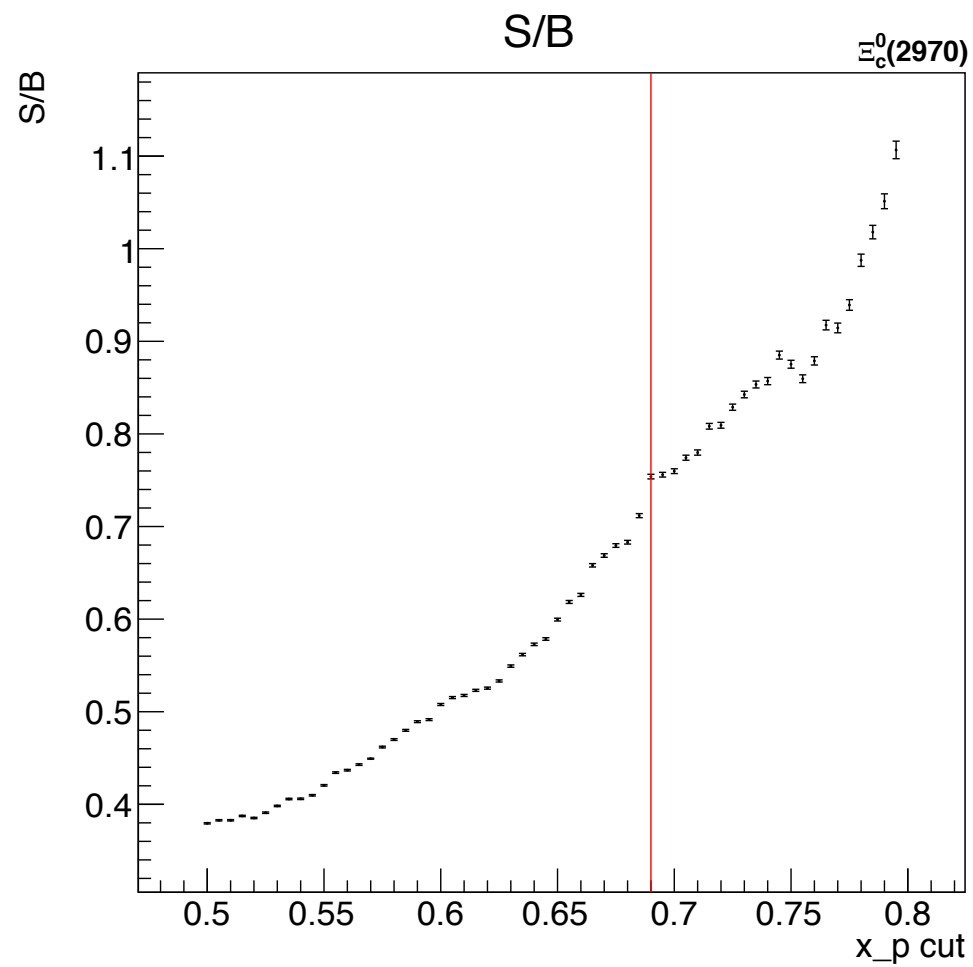


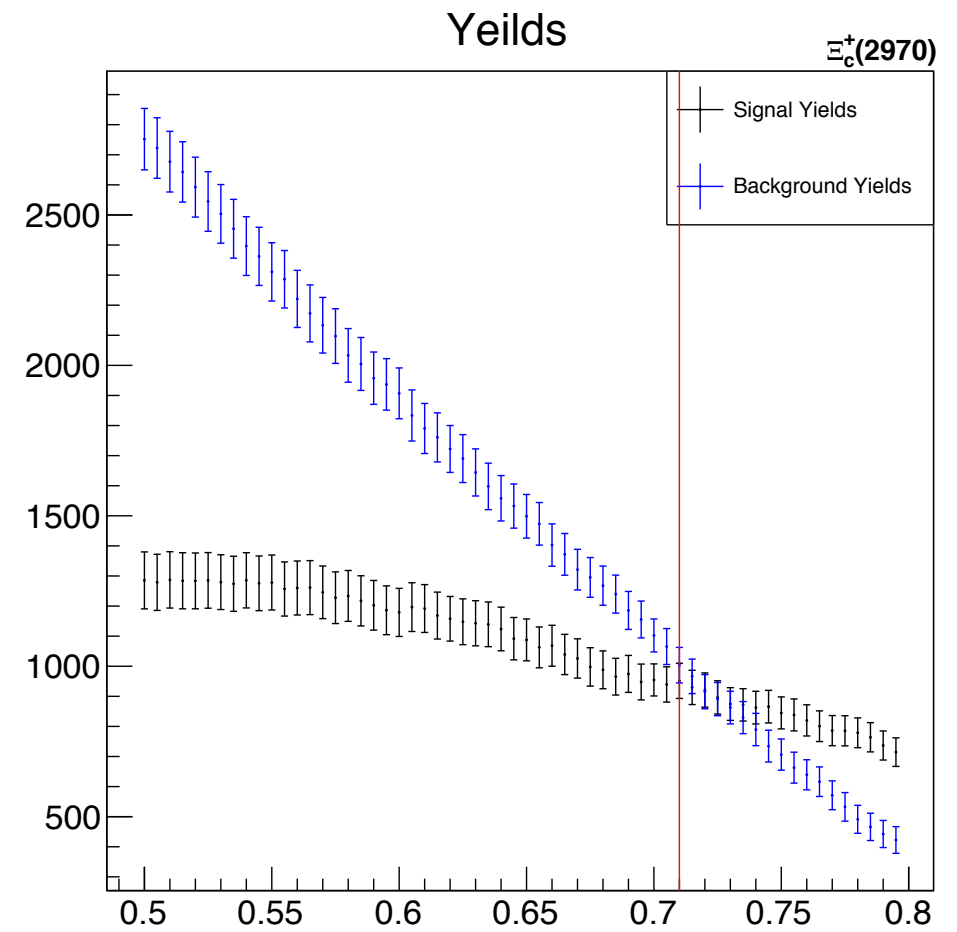
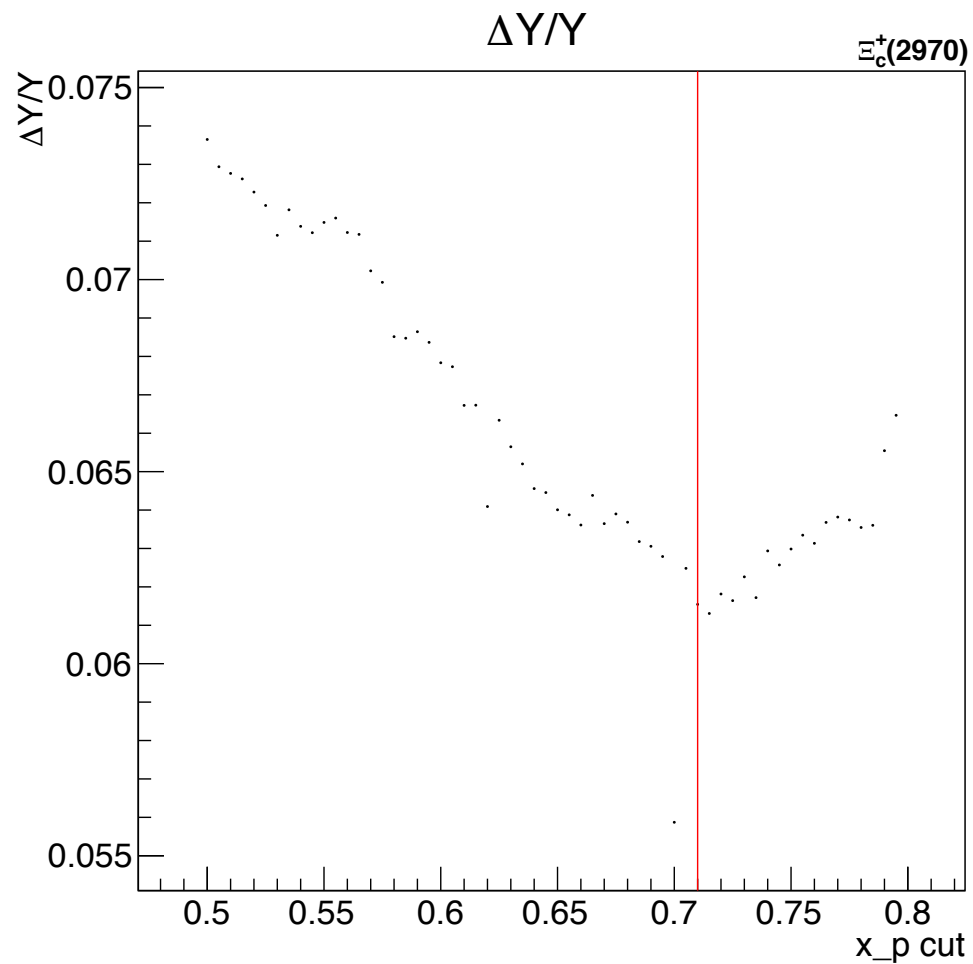
$\Xi_c^+(2815)$



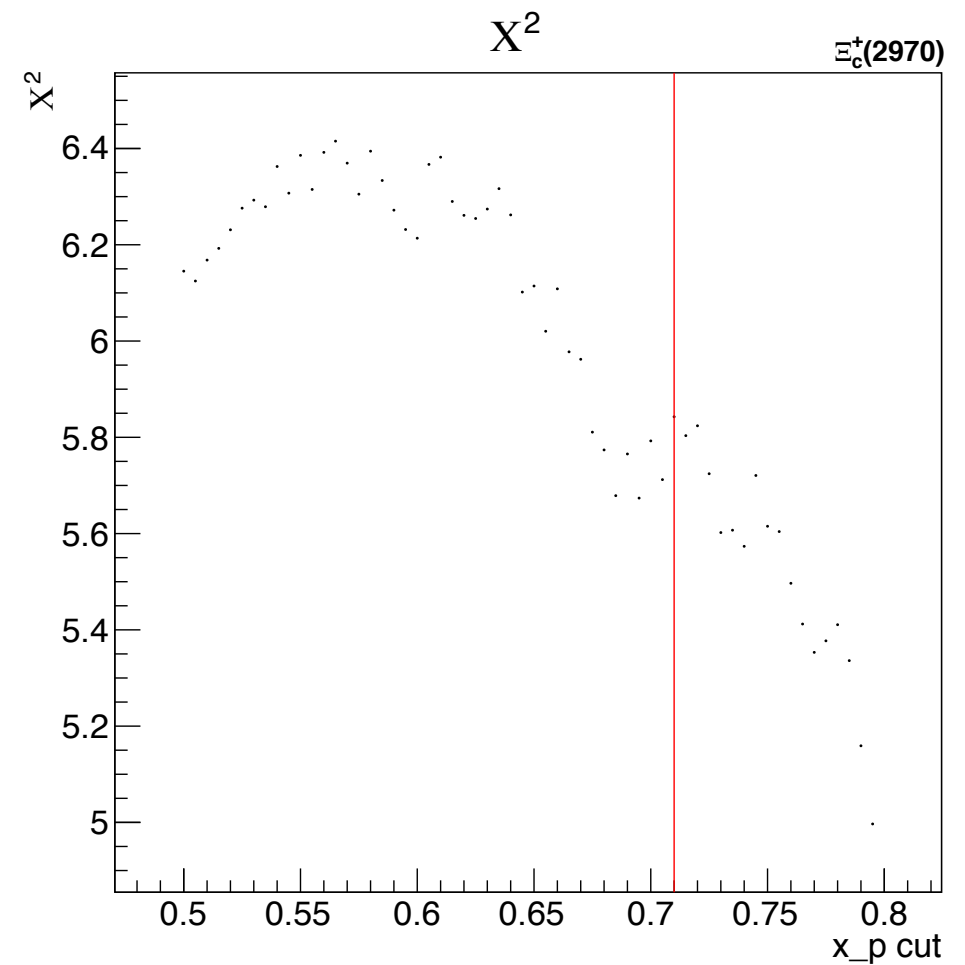
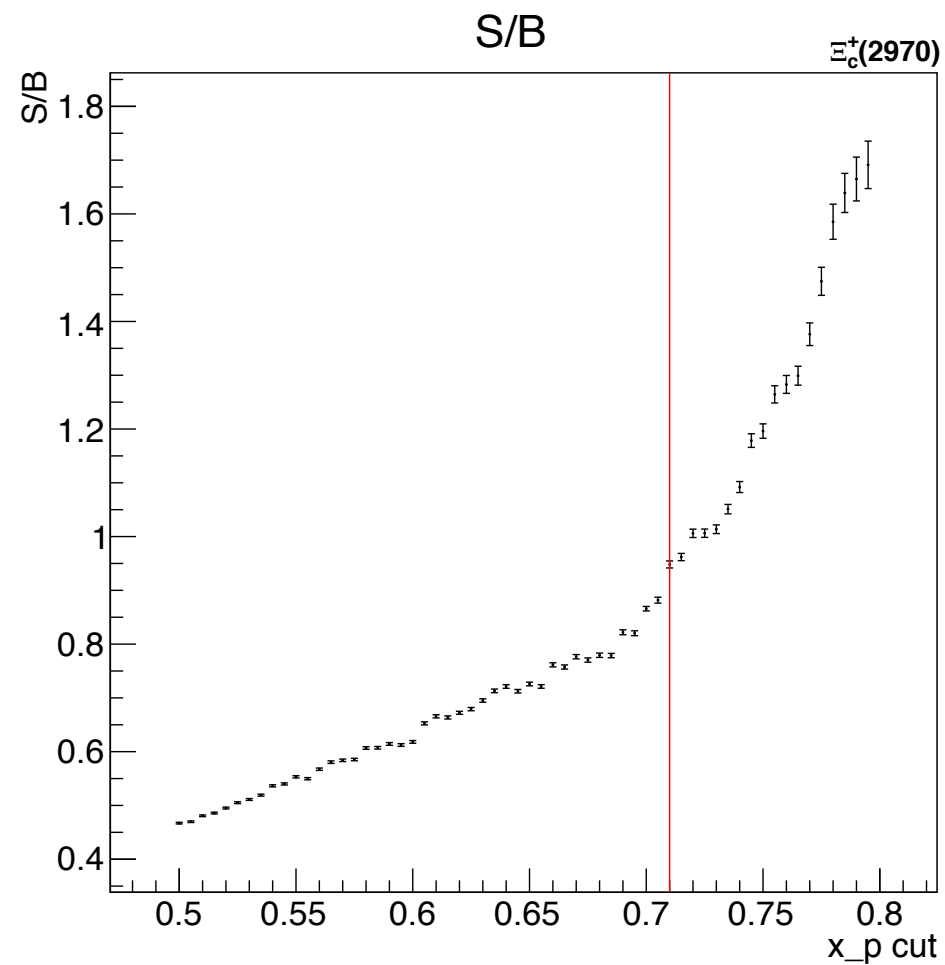


$\Xi_c^0(2970)$





$\Xi_c^+(2970)$



# Conclusion

- xp cut scan is finished.
- xp cut value is fixed.
  - For  $\Xi_c(2815)$ , xp cut = 0.55
  - For  $\Xi_c(2970)$ , xp cut = 0.7

# To do

- I am working for signal MC to study angle dependency of efficiency and mass resolution.